Electronic Version

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[c1] A method for determining a subsurface formation property, comprising:

- determining a volume fraction of a layer in a multielectrical-layer model for an anisotropic region of the formation, wherein the multi-electrical-layer model includes a relative-lower-resistivity layer and a relativehigher-resistivity layer and the determining is based on a resistivity measurement;
- layer and a resistivity for the relative-higher-resistivity layer based on the volume fraction and bulk resistivity measurements of the anisotropic region, wherein the bulk resistivity measurement include a horizontal resistivity measurement or a vertical resistivity measurement; and
- determining the formation property based on the volume fraction, the resistivity of the relative-lower-resistivity layer, the resistivity of the relative-higher-resistivity layer, a porosity measurement of the anisotropic region, and the bulk resistivity measurements.
- [c2] The method of claim 1, wherein the formation property

is a total water saturation.

[c3] The method of claim 2, wherein the water saturation is determined according to:

$$S_{w} = 1 - \frac{\phi_{\tau} - \left[(1 - VF) \sqrt{\frac{R_{w}}{R_{hr}}} + VF \sqrt{\frac{R_{w}}{R_{w}}} \right]}{\phi_{\tau}}$$

wherein $S_{\rm wt}$ is the total water saturation, \Box is the total porosity of the anisotropic region, VF is the volume fraction of the relative-lower-resistivity layer, $R_{\rm hr}$ is the resistivity of the relative-higher-resistivity layer, $R_{\rm hr}$ is the resistivity of the relative-lower-resistivity layer, and $R_{\rm w}$ is a resistivity of formation water.

- [c4] The method of claim 1, wherein the formation property is a bulk hydrocarbon volume.
- [c5] The method of claim 4, wherein the bulk volume of hydrocarbon is determined according to:

$$BVH = \phi_r - [(1 - VF)\sqrt{\frac{R_w}{R_{hr}}} + VF\sqrt{\frac{R_w}{R_h}}]$$

wherein BVH is the bulk hydrocarbon volume, \Box is the total porosity of the anisotropic region, VF is the volume fraction of the relative-lower-resistivity layers, R is the resistivity of the relative-higher-resistivity layer, R is

the resistivity of the relative-lower-resistivity layer, and R_{w} is a resistivity of formation water.

- [c6] The method of claim 1, wherein the volume fraction is of the relative-lower-resistivity layer.
- [c7] The method of claim 1, wherein the resistivity measurement is a high-resolution measurement.
- [08] The method of claim 7, wherein the determination of a volume fraction includes identifying bed boundaries based on the high-resolution resistivity measurement.
- [09] The method of claim 8, wherein identifying the bed boundaries includes finding inflection points on a derivative curve of the high-resolution resistivity measurement as a function of a borehole axial depth.
- [c10] The method of claim 1, wherein the volume fraction is determined by summing thicknesses of thin layers having similar electrical properties.
- [C11] The method of claim 1, wherein determination of the formation property is further based on a dual-water model or NMR data.
- [c12] The method of claim 1, wherein the volume fraction or the formation property is determined within a depth or time index interval.

[c13] A system for determining a subsurface formation property, comprising:

a computer system adapted to process a program including instructions for: determining a volume fraction of a layer in a multi-electrical-layer model for an anisotropic region of the formation, wherein the multi-electrical-layer model comprises a relative-lower-resistivity layer and a relative-higher-resistivity layer and the determining is based on a resistivity measurement;

layer and a resistivity for the relative-lower-resistivity layer based on the volume fraction and bulk resistivity measurements of the anisotropic region, wherein the bulk resistivity measurements include a horizontal resistivity measurement or a vertical resistivity measurement; and

determining the formation property based on the volume fraction, the resistivity of the relative-lower-resistivity layer, the resistivity of the relative-higher-resistivity layer, a porosity measurement of the anisotropic region, and the bulk resistivity measurements.

[C14] The system of claim 13, wherein the formation property is a total water saturation.

[c15] The system of claim 14, wherein the water saturation is determined according to:

$$S_{we} = 1 - \frac{\phi_{\tau} - \left[(1 - VF) \sqrt{\frac{R_{w}}{R_{w}}} + VF \sqrt{\frac{R_{w}}{R_{w}}} \right]}{\phi_{\tau}}$$

wherein S_{wt} is the total water saturation, $\phi_{\overline{x}}$

is the total porosity of the anisotropic region, VF is the volume fraction of the relative-lower-resistivity layer, $R_{\rm hr}$ is the resistivity of the relative-higher-resistivity layer, $R_{\rm lr}$ is the resistivity of the relative-lower-resistivity layer, and $R_{\rm w}$ is a resistivity of formation water.

- [c16] The system of claim 13, wherein the formation property is a bulk hydrocarbon volume.
- [c17] The system of claim 16, wherein the bulk volume of hydrocarbon is determined according to:

$$BVH = \phi_r - [(1 - VF)\sqrt{\frac{R_w}{R_{hr}}} + VF\sqrt{\frac{R_w}{R_s}}]$$

wherein BVH is the bulk hydrocarbon volume, ϕ_T

is the total porosity of the anisotropic region, VF is the volume fraction of the relative-lower-resistivity layer, R hr

is the resistivity of the relative-higher-resistivity layer, $R_{\rm lr}$ is the resistivity of the relative-lower-resistivity layer, and $R_{\rm w}$ is a resistivity of formation water.

- [c18] The system of claim 13, wherein the volume fraction is of the relative-low-resistivity layer.
- [c19] The system of claim 13, wherein the resistivity measure—ment is a high-resolution measurement.
- [c20] The system of claim 19, wherein determination of a volume fraction includes identifying bed boundaries based on the high-resolution resistivity measurement.
- [c21] The system of claim 20, wherein identifying the bed boundaries includes finding inflection points on a derivative curve of the high-resolution resistivity measurement as a function of a borehole axial depth.
- [c22] The system of claim 13, wherein the volume fraction is determined by summing thicknesses of thin layers having similar electrical properties.
- [c23] The system of claim 13, wherein determination of the formation property is based on a dual-water model or NMR data.
- [c24] The system of claim 13, wherein the volume fraction or the formation property is determined within a depth or

time index.